

AONS66916

100V N-Channel AlphaSGT™

General Description

- $\bullet \ \mathsf{Trench} \ \mathsf{Power} \ \mathsf{AlphaSGT}^{\mathsf{TM}} \ \mathsf{technology}$
- $\bullet \ Low \ R_{DS(ON)}$
- · Low Gate Charge
- Optimized for fast-switching applications
- RoHS and Halogen-Free Compliant

Applications

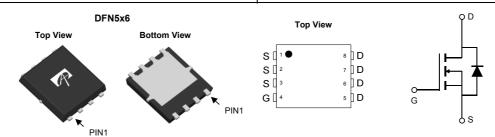
- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

Product Summary

 $\begin{array}{ll} V_{DS} & 100V \\ I_{D} \; (at \, V_{GS} \! = \! 10V) & 100A \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 10V) & < 3.6 m\Omega \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 6V) & < 5 m\Omega \end{array}$

100% UIS Tested 100% Rg Tested





Orderable Part Number	Number Package Type		Minimum Order Quantity		
AONS66916	DFN 5x6	Tape & Reel	3000		

Parameter		Symbol	Maximum	Units	
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage	;	V _{GS}	±20	V	
Continuous Drain T _C =25°C			100		
Current ^G	T _C =100°C	I _D	100	A	
Pulsed Drain Current C		I _{DM}	400		
Continuous Drain	T _A =25°C		30	А	
Current	T _A =70°C	IDSM	24	A	
Avalanche Current ^C	•	I _{AS}	70	Α	
Avalanche energy	L=0.1mH ^C	E _{AS}	245	mJ	
	T _C =25°C	В	215	14/	
Power Dissipation ^B	T _C =100°C	$-P_{D}$	86	W	
	T _A =25°C	В	6.2	W	
Power Dissipation A	T _A =70°C	P _{DSM}	4.0		
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 150	°C	

Thermal Characteristics						
Parameter		Symbol	Тур Мах		Units	
Maximum Junction-to-Ambient A	t ≤ 10s	D	15	20	°C/W	
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	40	50	°C/W	
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.43	0.58	°C/W	



Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC I	PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V		100			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =100V, V _{GS} =0V				1	
			T _J =55°C			5	μΑ
I_{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$		2.2	2.9	3.6	V
	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =20A			3.0	3.6	mΩ
R _{DS(ON)}			T _J =125°C		5.0	6.0	11177
		V_{GS} =6V, I_D =20A			3.8	5.0	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =20A			100		S
V_{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V			0.67	1	V
Is	Maximum Body-Diode Continuous Cur	rent ^G			100	Α	
DYNAMI	CPARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =50V, f=1MHz f=1MHz			5325		pF
Coss	Output Capacitance				1240		pF
C _{rss}	Reverse Transfer Capacitance				16		pF
R_g	Gate resistance			0.3	0.65	1.2	Ω
SWITCH	NG PARAMETERS	•	·		•	•	•
Q _g (10V)	Total Gate Charge	V _{GS} =10V, V _{DS} =50V, I _D =20A			67	95	nC
Q_{gs}	Gate Source Charge				19		nC
Q_{gd}	Gate Drain Charge				9		nC
t _{D(on)}	Turn-On DelayTime	V_{GS} =10V, V_{DS} =50V, R_L =2.5 Ω , R_{GEN} =3 Ω			18		ns
t_r	Turn-On Rise Time				7		ns
$t_{D(off)}$	Turn-Off DelayTime				30		ns
t _f	Turn-Off Fall Time				10		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =20A, di/dt=500A/μs		-	42		ns
Q_{rr}	Body Diode Reverse Recovery Charge	e I _F =20A, di/dt=500A/μs		-	215		nC

A. The value of R_{BJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A =25° C. The Power dissipation P_{DSM} is based on R _{8JA} t≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design.

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B. The power dissipation P_D is based on T_{J(MAX)}=150° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(MAX)}$ =150 $^{\circ}$ C.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

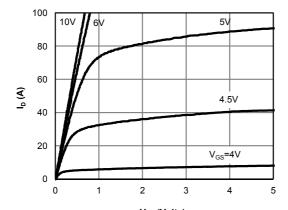
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{U(MAX)}=150° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

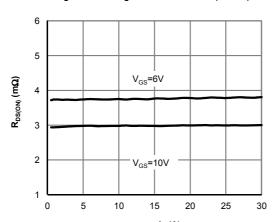
H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.



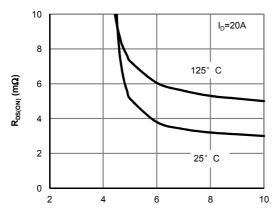
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



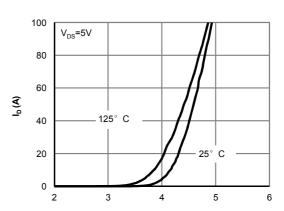
 $V_{\rm DS}$ (Volts) Figure 1: On-Region Characteristics (Note E)



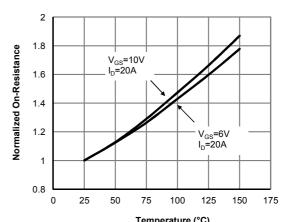
 $\label{eq:local_local} \textbf{I}_{\text{D}}\left(\textbf{A}\right)$ Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



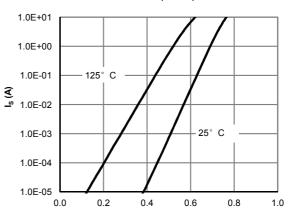
V_{GS} (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



V_{GS} (Volts) Figure 2: Transfer Characteristics (Note E)



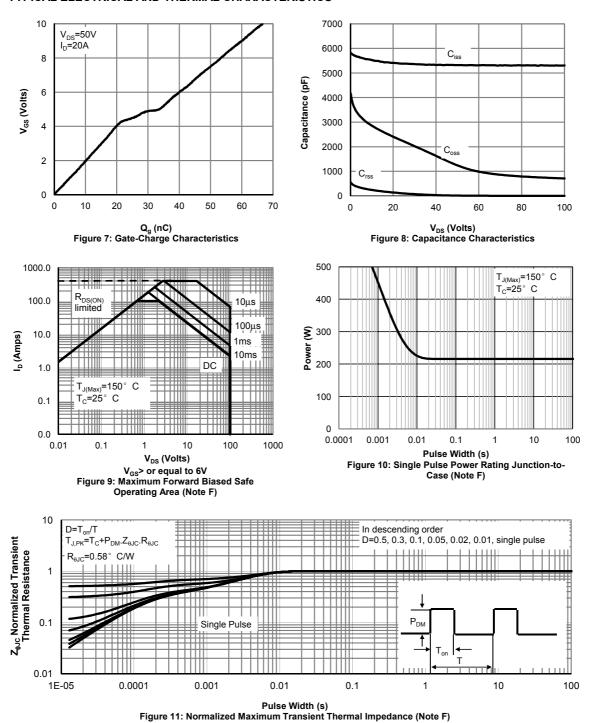
Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)



V_{SD} (Volts) Figure 6: Body-Diode Characteristics (Note E)



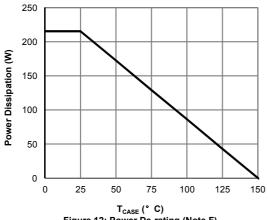
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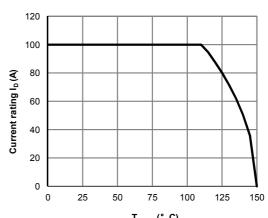
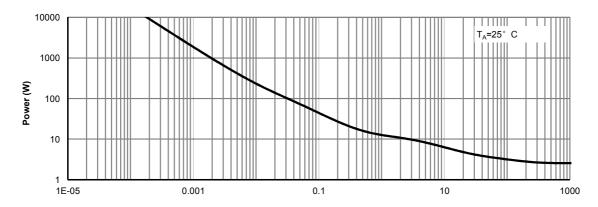
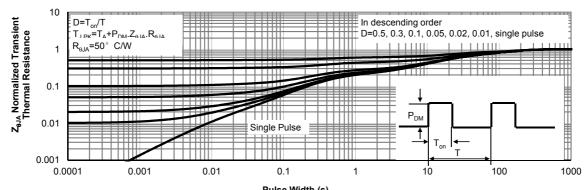


Figure 12: Power De-rating (Note F)

T_{CASE} (° C)
Figure 13: Current De-rating (Note F)



Pulse Width (s) Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)



Pulse Width (s)
Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

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Figure A: Gate Charge Test Circuit & Waveforms

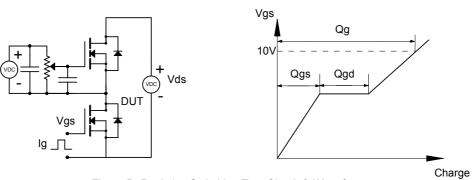


Figure B: Resistive Switching Test Circuit & Waveforms

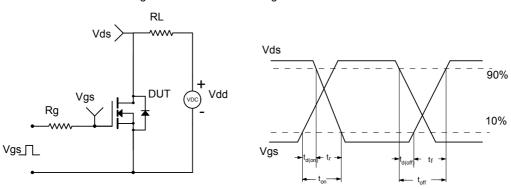


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

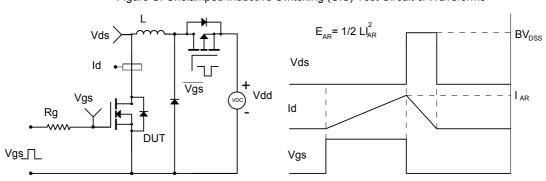
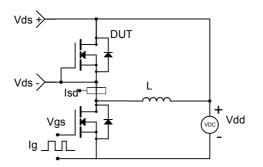
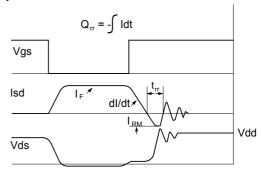


Figure D: Diode Recovery Test Circuit & Waveforms





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